

Departments

Ron Anderson, Editor

Calendar of Meetings: Organizers of scientific meetings wishing to inform the readers of *Powder Diffraction* of their plans are welcome to submit meeting announcements to the Departments Editor. The announcements may be accompanied by text giving particulars of the meeting and programs. The additional matter in such expanded announcements will be printed on a space-available basis. While we will accept announcements of meetings on topics even remotely related to powder diffraction as a service to our readers, the editors, at their discretion, reserve the right to reject announcements of meetings concerning totally unrelated subjects. The deadlines in the instructions to authors apply to meeting announcements. There is no charge for this service. Meeting organizers wishing to purchase advertisements are invited to contact *Powder Diffraction's* Advertising Manager.

Commercial Announcements: This column is reserved for the commercial use of individuals and firms providing products or services to the powder diffraction community. Press releases and new product announcements are appropriate and welcome. The insertions, up to 300 words or the equivalent if a figure is included, should give a price, if appropriate, and the contributor's full name and address. Full or partial inclusion will be on a space-available basis at the editor's discretion, with preference given to advertising agencies and companies that purchase advertisements in *Powder Diffraction*. Send contributions to the departments editor. *Powder Diffraction* can assume no liability for the accuracy of the claims made.

Short Courses and Workshops: This journal will print announcements of short courses and workshops in fields relating to the interests of its readers. Organizers of such programs are invited to send short descriptive announcements to the Departments Editor. See below for the format and size of contributions that will be printed free of charge. The editors reserve the right to determine suitability for printing with regard to course or workshop content.

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Calendar of Meetings

1986

Synchrotron Radiation for X-Ray Crystallography June 10-19, 1986 Erice, Sicily, Italy

Topics are synchrotron techniques and methods of use in crystallography. Papers in English. Contact: Lodovico Riva di Sanseveriero, Piazza di Porta S. Donato 1, 40127 Bologna, Italy.

American Crystallographic Association Meeting June 22-27, 1986 Hamilton, Ontario, Canada

This meeting will be held at McMaster University. Contact: Dr. I. D. Brown, Institute for Materials Research, McMaster University, 1280 Main Street West, Hamilton, Ontario, Canada L8S 4M1.

14th International Mineralogical Association July 13-18, 1986 Stanford, California, U.S.A.

Details from I.M.A. 1986, PO Box 183, Stony Brook, NY 11790, U.S.A.

Tenth International CODATA Conference July 14-17, 1986 Ottawa, Ontario, Canada

Theme is "The Computer Handling and Dissemination of Data." Scientific and technical source database developers will present demonstrations of interest to their colleagues on machines ranging from micros to mainframes. Contact: Huguette Lacoste, Executive Secretary, CODATA '86, National Research Council Canada, Ottawa, Ontario, Canada K1A 0R6 (613) 993-9009.

International Conference on Crystal Growth July 14-18, 1986 York, England

Contact: Dr. F. W. Ainger, Conference Secretariat, Plessey Research (Caswell) Ltd., Allen Clark Research Centre, Caswell, Towcester, Northants NN12 8EQ, England.

Nondestructive Characterization of Materials July 21-23, 1986 Montreal, P.Q., Canada

This symposium will embrace all aspects of nondestructive materials characterization and its applications. X-ray methods are highlighted in the first circular. Details from Mme. Gladys Cyr, Industrial Materials Research Institute (NRCC), 75 Boul. DeMontagne, Boucherville, Quebec, Canada J4B 6Y4 (514) 641-2280.

1986 Denver X-Ray Conference
August 4-8, 1986
Denver, Colorado, U.S.A.

The 35th Annual Denver Conference on Applications of X-ray Analysis will be held at the University of Denver. See advertisement elsewhere in this issue (page 86) for preliminary program. For additional information contact: Denver X-ray Conference Secretary, DRI/CAMS, University of Denver, Denver, Colorado 80208, U.S.A. (303) 871-2141.

Tenth European Crystallographic Meeting
August 5-9, 1986
Wroclaw, Poland

Contact: Tenth European Crystallographic Meeting, Institute for Low Temperature and Structure Research, Plac Katedralny 1, 50-950 Wroclaw, Poland

XIIth Conference on Applied Crystallography
August 10-14, 1986
Cieszyn, Poland

Contact: Dr. E. Lagiewka, XIIth Conference on Applied Crystallography, Uniwersytet Slaski, Instytut Fizyki i Chemii Metali, ul. Bankowa 12, 40-007 Katowice, Poland

Electron Microscopy Society of America/Microbeam Analysis Society
Annual Meeting
August 11-15, 1986

Albuquerque, New Mexico, U.S.A.

Transmission and scanning electron microscopy and diffraction plus electron column instrument papers. Papers are divided evenly between physical and biological applications. Numerous symposia. Emphasis this year on SEM. Large instrument show. Contact: M. J. Carr (EMSA) or Wm. Chambers (MAS) Sandia National Laboratories, Division 1822, P.O. Box 5800, Albuquerque, NM 87185, U.S.A. (505) 846-1405.

10th International Symposium on Microchemical Techniques

August 25-29, 1986

Antwerp, Belgium

Contact: Dr. R. deWolfs, University of Antwerp, Universiteitsplein 1, B-2610, Antwerp-Wilrijk, Belgium

11th International Congress on Electron Microscopy

August 31-September 7, 1986

Kyoto, Japan

Contact: Secretariat, XI ICEM, Department of Anatomy, Faculty of Medicine, Kyoto University, Konoecho Yoshida Sakyo-ku, Kyoto 606, Japan.

5th Europhysics Topical Conference on Lattice Defects in Ionic Crystals
September 8-12, 1986
Madrid, Spain

Contact: Mr. F. J. Lopez, Dept. Optica y Estructura Materia, Universidad Autonoma de Madrid, Cantoblanco E-28049, Madrid, Spain.

The Silver Jubilee Eastern Analytical Symposium
October 6-10, 1986
New York, NY U.S.A.

Contact: Dr. S. David Kline, EAS Publicity, 642 Cranbury Cross Road, North Brunswick, NJ 08902, U.S.A.

International Conference on Residual Stress
October 15-17, 1986
Germisch-Partenkirchen, Federal Republic of Germany

In previous national and European conferences, fundamental and applied aspects and problems from the multi-parametric field of residual stresses were emphasized. In accord with the aim of the preceding conferences, ICRS will provide an up to date comprehensive assessment of recent progress and unsolved problems in the field of residual stresses regarding both engineering and materials science aspects. The conference will apply a unified approach to all important areas of residual stresses in metals, ceramics, polymers and composites.

Contact: Conference Secretariat, Deutsche Gesellschaft fur Metalkunde e.V., Adenaueralee 21, D-6370 Oberursel 1, Tel: 06171/4081

1987

Colloquium Spectroscopium Internationale
June 22-27, 1987
Toronto, Canada

75th Anniversary Convention of the South African Chemical Institute
Durban, South Africa

Pittsburgh Conference on Analytical Chemistry and Applied Spectroscopy
March 9-13, 1987
Atlantic City, NJ, U.S.A.

36th Annual Denver X-Ray Conference
August 3-7, 1987
Snowmass, Colorado, U.S.A.

Geological Society of America
October 26-30, 1987
Phoenix, AZ, U.S.A.

XIV General Assembly and International Congress of Crystallography
August 12-20, 1987
Perth, Western Australia

X-Ray Powder Diffractometry

August 21–22, 1987

Perth, Western Australia

Contact: Dr. Brian O'Connor, Western Australian Institute of Technology, Kent Street, Bentley, WA 6102, Australia.

International Union of Crystallography Satellite Meeting on X-Ray Powder Diffractometry

York, Western Australia

Thursday August 20–Saturday August 22, 1987

Scope of Meeting

The meeting will comprise a symposium on automated data acquisition and analytical procedures in industry with special reference to:

- (i) data acquisition
- (ii) automated profile processing and
- (iii) quantitative studies of materials, including Rietveld methods.

Timing and Proposed Venue

The satellite meeting is to be held in the town of York, Western Australia, following the International Union of Crystallography (IUCr) Congress in Perth from Wednesday, August 12th to Thursday, August 20th, 1987. Satellite meeting attendees will travel to York after the Congress closing ceremony on Thursday, August 20. The satellite meeting will commence on the evening of Thursday, August 20 and will formally conclude on the evening of Saturday, August 22. It is intended to offer a social program of outdoor and cultural activities on Sunday, August 23 for participants and families who do not return to Perth immediately following the conclusion of the satellite meeting.

York was founded in 1830 during the early days of the Western Australian colony established by Britain. The original character of the town has been retained by preserving various buildings which, together with the emphasis on farming and crafts within the community, makes York a most welcome place for those seeking relief from the pressures of city life. The town is located 97km east of Perth and is reached by a pleasant journey of several hours duration (by car, rail or bus) through the Australian bushland. York has been proposed as the satellite meeting venue in order to give attendees a change of scene following the conclusion of the Congress.

Proposed Schedule for Submission of Papers/Registration

First Circular

General details of meeting, including list of keynote speakers and call for papers — distribution March, 1986.

Second Circular

Detailed meeting plan and call for registration — distribution September, 1986.

Further Information and Requests for Receipt of First Circular

To be directed to the meeting convener:

Dr. Brian O'Connor
School of Physics and Geosciences
Western Australian Institute of Technology
Kent Street
Bentley, W.A. 6102
Australia

Please mark envelope 'Attention SMXPD'

Telephone: (619) 350-7192

Telex: AA92983

Meeting Reports

The 6th Australasian Schools and Conference on X-Ray Analysis and Surface Analysis

Sydney, Australia February 10–14 1986

This meeting was the fourth of its kind to be organised by the AXAA, Australian X-Ray Analytical Association, and on this occasion the meeting was held at the University of New South Wales. The AXAA is a National Association of Scientists who are essentially involved in the use of X-ray techniques for materials characterisation. The AXAA is a very active organisation with chapters in several of the larger cities in Australia. The total membership of AXAA currently stands at around 400.

The program comprised three days of schools and refresher courses, followed by two days of invited lectures. The paper sessions also included poster presentations. The schools program consisted of four main streams: X-Ray Powder Diffraction, X-Ray Fluorescence Spectrometry, Surface Analysis techniques and a school on Sampling. Each of the schools was well attended with the Diffraction schools attracting the biggest audience. Total attendance at the meeting was about 220. Parallel sessions were employed in the papers session in order to accommodate the forty or so contributions which were given.

The plenary sessions attracted a significant overseas involvement and included papers on 'Development of XRF Standard methods — by Dr. Kieth Norrish of CSIRO Division of Soils, Adelaide, Australia'; 'Sampling From Moving Streams' — by Dr. A. Royle, University of Leeds, U.K.'; 'Present State of Practical Surface Analysis by AES, XPS, ISS and SIMS — by Dr. S. Hofmann of the Max Planck Institute, Stuttgart, Germany' and 'The Impact of Personal and Mini-Computers on the Automated Search/Match Process — by Dr. Ron Jenkins of the JCPDS-International Centre for Diffraction Data, Swarthmore, PA, USA'. Other overseas speakers included Professor Horst Ebel and Dr. Maria Ebel from the Technical University in Vienna, Austria, Dr. John Kikkert from Philips in Almelo, The Netherlands and Dr. Stephen Reed from Cambridge, England.

All of the sessions were extremely lively and covered all aspects of the traditional uses of X-ray analytical methods as well as newer developments. The conference dinner was